ABSTRACT OF THE DISCLOSURE

The present invention relates generally to an improvement in the ability of test

systems to test bit processing capacities of electronic devices, and in particular an

improvement in their ability to measure a signal propagation delay through an object

connected to an optoelectronic device. The present invention includes determining for

how long after a specific bit or bit group is transmitted by an optical transceiver the bit

or bit group is received at the other end of the object connected to the optical

transceiver.

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Docket No. 15436.253.73.1.1